

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 240093US-2 DIV		SERIAL NO.	
<div style="display: flex; align-items: center; justify-content: center;"> <div style="border: 2px solid black; border-radius: 50%; padding: 10px; text-align: center; margin: 0 10px;"> OIPF SEP 07 2004 </div> <div style="text-align: center;"> LIST OF REFERENCES CITED BY APPLICANT </div> </div>				APPLICANT TSUNEO KUROTORI, ET AL.			
				FILING DATE HEREWITH		GROUP 2852	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
SL	AA	4,052,959	10/1977	Hayashi et al.	399	249	
SL	AB	5,359,398	10/1994	Echigo et al	399	71	
SL	AC	5,374,980	12/1994	Kubo et al.	399	233	
SL	AD	6,219,500	04/2001	Byun, S.	399	57	2/7/00
SL	AE	6,370,347	04/2002	Shin et al.	399	249	8/23/00
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
SL	AO	7-209922	08/11/95	Japan (with English Abstract)			x
SL	AP	7-152254	06/16/95	Japan (with English Abstract)			x
SL	AQ	7-21935	01/24/95	Japan (with English Abstract)			x
SL	AR	2000-47490	02/18/00	Japan (with English Abstract)			x
SL	AS	2000-242088	09/08/00	Japan (with English Abstract)			x
SL	AT	2001-228717	08/24/01	Japan (with English Abstract)			x
SL	AU	01-206379	08/1989	Japan			
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner <u>Sophia S. Chen</u>					Date Considered <u>10/13/04</u>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							